IN THE SPECIFICATION

Please amend the paragraph beginning at page 36, line 12, as follows:

That is to say, for the results of X-ray diffraction measurement thus obtained, the presence of the specified crystal structure as defined in the present invention can be confirmed by confirming that the respective peaks from the reference peak PO to P5 appear in the above-mentioned angle ranges. For example, in X-ray diffraction measurement using a CuKα as an X-ray source, a diffraction peak is observed within the range (R0) of the diffraction angle (2θ) of from 21.30° to 22.50°, and when this diffraction peak is taken as a reference diffraction peak (P0) and 5 diffraction angle ranges derived from the Bragg angle (θs) of P0 are taken as R1, R2, R3, R4 and R5, at least one diffraction peak exists in these 5 ranges, with the proviso that P0 has an intensity of 20% or more by the diffraction peak height ratio, based on the strongest diffraction peak of said 6 or more crystal phase-derived diffraction peaks, and the other peaks has an intensity of 9% or more by the diffraction peak height ratio, wherein when two or more diffraction peaks exist in one angle range, a peak higher in intensity is selected.

This crystal phase is a crystal phase different from merwinite described in non-patent document 1 and non-patent document 2. The above-mentioned angle ranges Rl to R5 are more preferably as follows in which the deviation of the plane spacing associated with strain of the structure is taken as 1.0% without variation.

Rl : 2x arcsin {sin(θ0) / (0.720x1.010)} to
2 x arcsin {sin(θ0) / (0.720x0.990)}

R2: 2x arcsin {sin(θ0) / (0.698x1.010)} to

2 x arcsin {sin(θ0) / (0.698x0.990)}

R3: 2x arcsin {sin(θ0) / (0.592x1.010)) to

2 x arcsin {sin(θ0) / (0.592x0.990)}

R4: 2x arcsin {sin(θ0) / (0.572x1.010)} to

2 x arcsin {sin(θ0) / (0.572x0.990)}

R5: 2x arcsin {sin(θ0) / (0.500x1.010)} to

2 x arcsin {sin(θ0) / (0.500x0.990)}